ICATION

OIPE 15/389-2	PATENT APPL
IN THE UNITED STATES PA	ATENT AND TRADEMARK OFFICE
In re Application of:) : Examiner: ASSAF, FAYEZ G.
GLENN CLARKE ET AL.) TC/Art Unit: 2872
Application No.: 10/840,134)
Filed: 05/06/2004	·)
For: METHOD OF MAKING HIGHLY DISCRIMINATING OPTICAL EDGE FILTERS AND RESULTING PRODUCTS) :) July 21, 2005

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed PTO-1449 form. A copy of each listed document is enclosed, except for U.S. patents and published U.S. patent applications.

> I hereby certify that this correspondence is being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

July 21, 2005 **Date of Transmission**

Daniel D. Sierchio (Reg. No. 53,591)

Printed Name

Signature

Date of Signature

Applicants' undersigned attorney may be reached by telephone at (973) 597-2500.

All correspondence should continue to be directed to our address listed below.

Respectfully submitted,

Daniel D. Sierchio Attorney for Applicants

Registration No. 53,591

DOCKET ADMINISTRATOR Lowenstein Sandler PC 65 Livingston Avenue Roseland, NJ 07068

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) U.S. PATENT DOCUMENTS EXAMINER INITIAL REF DOCUMENT NUMBER DATE Docket Number (Optional) Application Number 10/840,134 Applicant(s) GLENN CLARKE ET AL. Filing Date 05/06/2004 U.S. PATENT DOCUMENTS FILING INITIAL REF DOCUMENT NUMBER DATE NAME CLASS SUBCLASS FILING APPROPRIES

EXAMINER	1	T	<u> </u>	S. PATENT DOCUMENTS			FILING DATE	
INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	IF APPROPRIATE	
		2005/0110999	05/26/05	Erdogan et al.	356	417		
		6,809,859	10/26/04	Erdogan et al.	359	359		
		4,142,958	03/06/79	Wei et al.	204	192		
		4,793,908	12/27/88	Scott et al.	204	192.26		
		6,649,208	11/18/03	Rodgers	427	10		
		6,704,130	03/09/04	Ford et al.	359	245		
		5,656,138	08/12/97	Scobey et al.	204	192.12		
······································		5,512,131	04/30/96	Kumar et al.	156	655.1		
41.11	Į		FOR	EIGN PATENT DOCUMENTS	. ! .		<u></u>	
EXAMINER	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION Yes No	
		OTHER	DOCUMENTS (I	ncluding Author, Title, Date, Pertin	ent Pages, Etc.,			
			al Coatings, I	ttering," Handbook of Opt Ed. By R.E. Hummel and k I, (CRC Press, Boca Rato	K.H. Guenth			
		Macleod, H. Angus, "Thin-Film Optical Filters," 3 rd Ed., Institute of Physics (2001)						
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Press, W.H., et al., The Levenberg-Marquardt method implemented name "mrqmin()", Numerical Recipes in C: The Art of Scientific Comed., Chapter 15, pp. 683-688 (1995)								
	Martin, P.J. et al., "Ion-beam-assisted deposition of thin films," Applied Optics, Vol. 22, No. 1, pp. 178-184 (1983)							
			<i>(1)</i> 1 <i>2</i>		10.05.10.0			

Examiner Signature Date Considered

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

"Interference Filters," Melles Griot, pp. 13.25-13.29

Form PTO-A820 (also form PTO-1449)

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional) Application Number 15789-2 10/840,134				
Applicant(s) Glenn Clarke et al.				
Filing Date 05/06/2004	Group Art Unit 2872			

U.S. PATENT DOCUMENTS EXAMINER INITIAL FILING DATE REF DOCUMENT NUMBER DATE NAME CLASS SUBCLASS IF APPROPRIATE 6,518,168 02/11/03 Clem et al. 438 623 5,900,160 05/04/99 Whitesides et al. 216 41 Krivokapic 427 304 6,623,803 09/23/03 05/12/92 Carrabba et al. 5,112,127 356 301 5,712,715 01/27/98 Erdogan et al. 359 8 **FOREIGN PATENT DOCUMENTS** TRANSLATION DATE CLASS SUBCLASS EXAMINER DOCUMENT NUMBER INITIAL OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) J.M.E. Harper, "Ion Beam Deposition," in Thin Film Processes, Ed. by J.L. Vossen and W. Kern, pp. 175-206 (Academic Press, New York, 1978).

U.J. Gibson, "Ion-Beam Processing of Optical Thin Films," in *Physics of Thin Films*, Vol. 13, Ed. by G. Hass and M.H. Fancombe, pp. 109-150 (Academic Press, New York, 1978).

J.M.E. Harper et al., "Modification of Thin Film Properties by Ion Bombardment During Deposition," in *Ion Bombardment Modification of Surfaces*, Ed. by O. Auciello and R. Kelly, from *Beam Modification of Materials*, Vol. 1, pp. 127-162 (Elsevier, Amsterdam, 1984).

W.H. Teukolsky et al., *Numerical Recipes*, "Numerical Recipes in C: The Art of Scientific Computing," 2nd ed., Cambridge University Press, Cambridge, Chapter 15.7, pp. 699-706 (1995).

Examiner Signature

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